

Scanning Platform

Imaging the nanoscale phase separation in V₂O₃ with scanning microwave impedance microscopy

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50 mV

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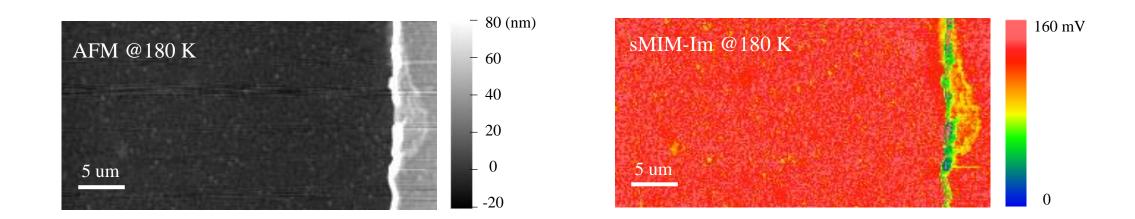
Introduction

Scanning Microwave Impedance Microscopy (sMIM)

- AFM-based near field scanning probe working at microwave frequency \bullet
- Probe the local conductivity/dielectric variation through AC microwave ۲ impedance measurement
- High spatial resolution (~50 nm) with subsurface sensing capability •

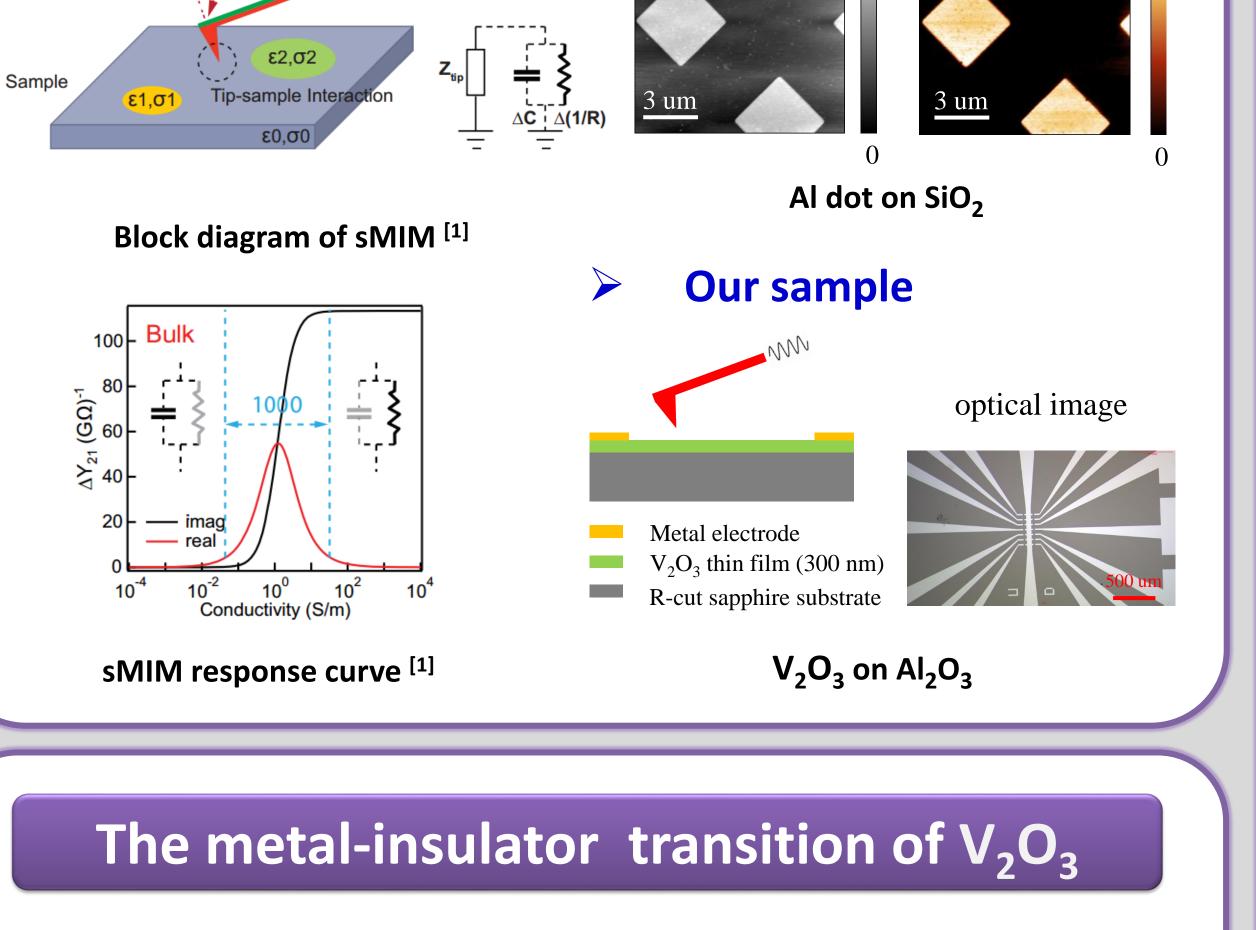
3 GHz 30 nm Microwave Electronics

Nanoscale phase separation in V_2O_3

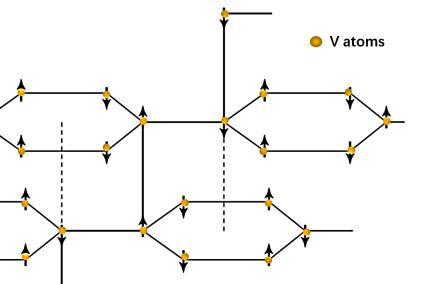


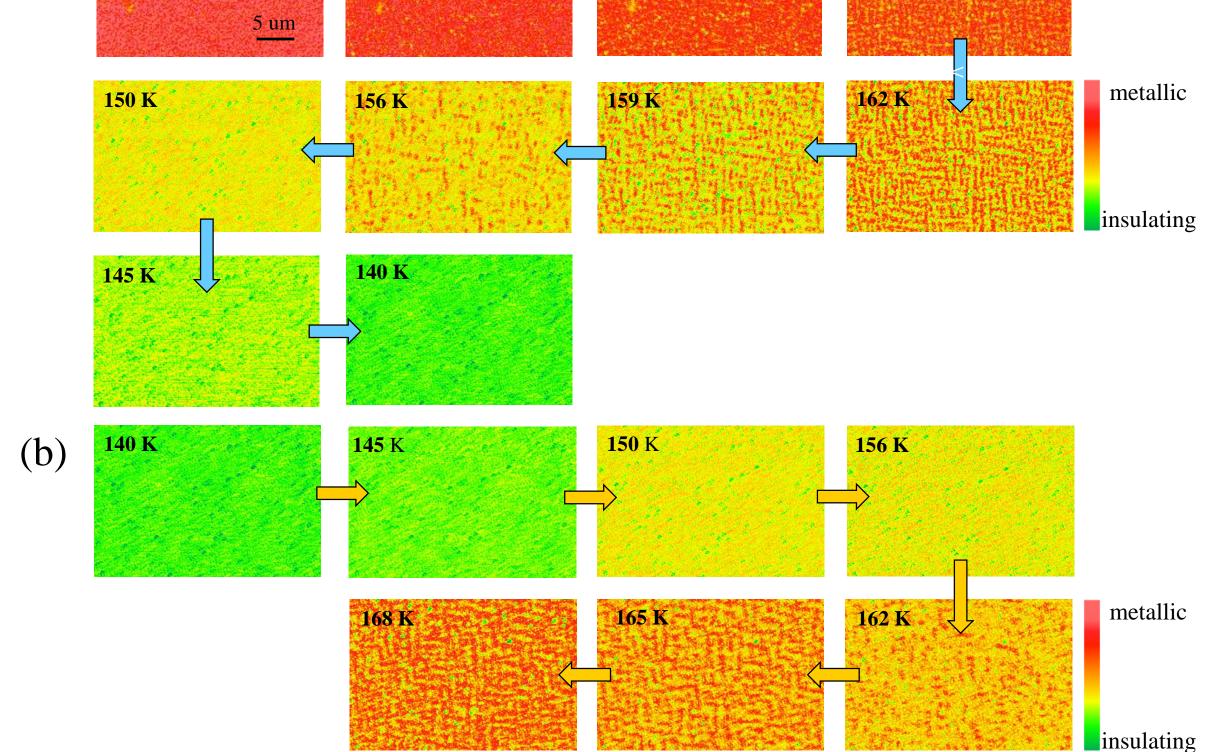
sMIM-Im signal normalized to an absolute reference by inclusion of a lithographically defined gold electrode within the imaging field of





- Canonical system with metal- insulator transition (MIT)
- 1st order MIT accompanied by a \bullet structural transition
- MIT mechanism: the structure driven Peierls transition? or Mott transition?

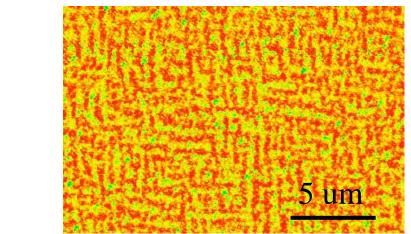




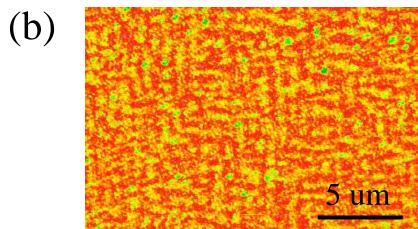
Temperature-dependent co-localized sMIM images (normalized) of nanoscale phase separation in V₂O₃ show bi-directional striped pattern



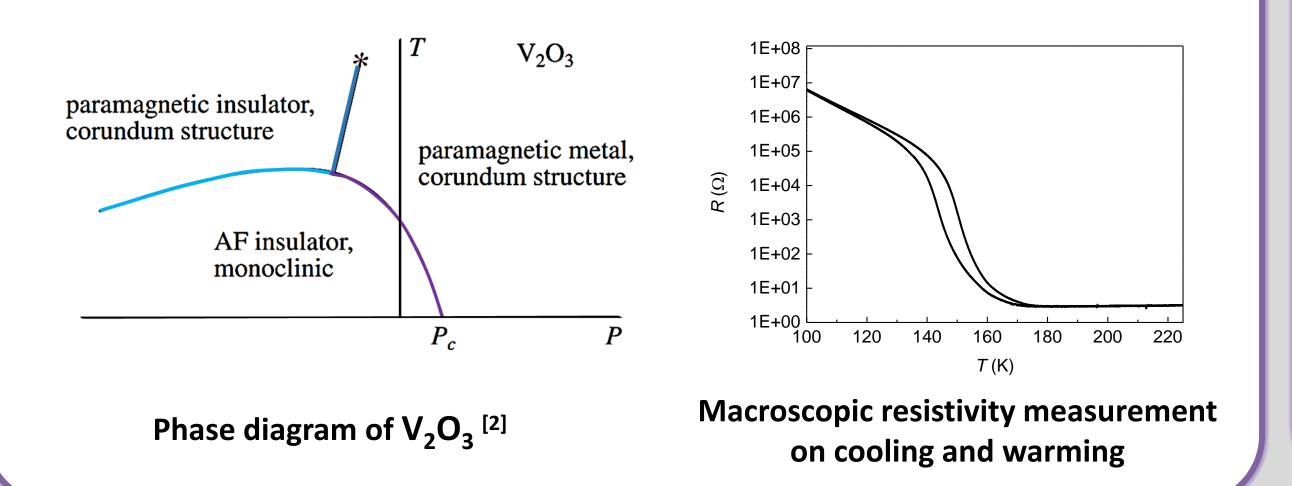
(a)



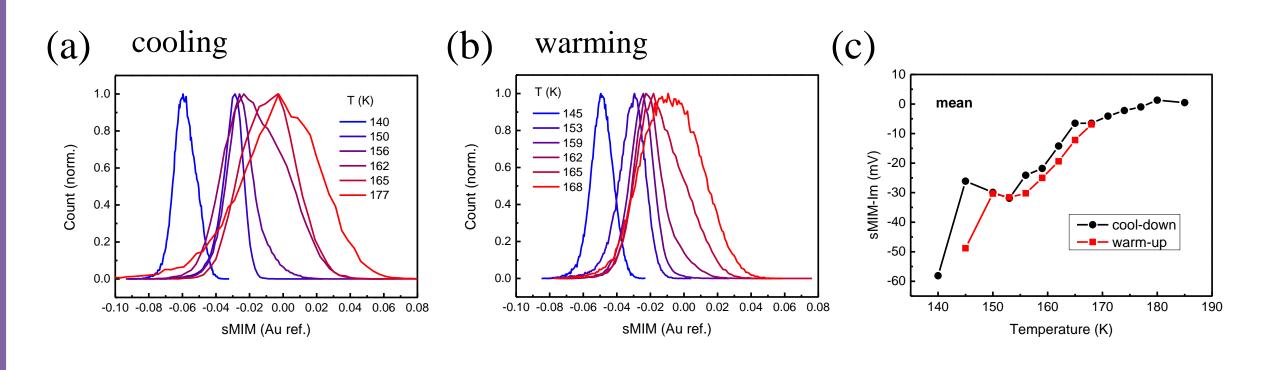
168 K (warming)







Nearly identical configuration of phase separation during (a) cooling and (b) warming indicates a strong phase pinning effect by substrate ^[3]



The measured sMIM signal level shows a continuous change with a thermal hysteresis consistent with the macroscopic resistivity measurement

Conclusions

- 1. The MIT in V₂O₃ was probed microscopically with sMIM displaying a bi-directional striped pattern of phase separation at micrometer scale.
- 2. The measured sMIM signal level shows a continuous change with temperature including the thermal hysteresis, facilitating a direct comparison with macroscopic resistivity measurement.
- **3.** Potential research application of sMIM to system with contrasting spatial conductivity, such as domain/domain walls in multiferroics and topological edge states in topological phases.

[1] Worasom, K. PhD thesis. "Imaging nanoscale electronic inhomogeneity with microwave impedance microscopy", Stanford, 2013.

